
FOREWORD

Special Section on Machine Vision and its Applications

The Tenth IAPR Conference on Machine Vision Applications, MVA2007, was held in the Institute of Industrial Science, The University of Tokyo, from May 16 through 18, 2007. Reflecting the growing expectation and demand for machine vision and its applications, the conference attracted 220 submissions from 36 countries/regions, among which 41 papers were selected for oral presentation and 96 for poster presentation. Inspired by the great success of the conference, we planned this special section, asking the conference participants as well as other researchers in this field to submit papers. We received 39 papers and through a rigorous review process we have selected 15 of these. We believe that the papers show the high quality of current machine vision research; the broad range of machine vision technologies; and its wide application to areas such as human-computer interaction, surveillance, inspection, assembly and so on. We would like to express our sincere gratitude to all the authors for their valuable contributions and to all the reviewers for their cooperation in completing the reviewing process under a tight schedule.

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Hiroshi Sako, Guest Chief Editor

Hiroshi Sako (*Member*) received the B.E. and M.E. degrees in mechanical engineering from Waseda University, Tokyo, Japan, in 1975 and 1977, respectively, and the Dr. Eng. degree from The University of Tokyo, in 1992. From 1992 to 1995, he was a Senior Research Scientist at the Hitachi Dublin Laboratory, Ireland. He is currently a Chief Researcher in the Hitachi Central Research Laboratory, Tokyo, where he directs image recognition and character recognition research groups. Since 1998, he has also been a Visiting Professor at the JAIST, Hokuriku Postgraduate University. Dr. Sako is a Fellow of the IEEE and a Fellow of the International Association for Pattern Recognition.

